


<b>Search Notes</b>  	<b>Application/Control No.</b>  10511040	<b>Applicant(s)/Patent Under Reexamination</b>  BARTH ET AL.
	<b>Examiner</b>  Cho, Jennifer Y	<b>Art Unit</b>  1621

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
East Search	7/8/07	JC
STIC Search	7/6/07	PS
Inventor Search	7/20/07	JC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner